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### What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

### Applications of "[Embedded - Microcontrollers](#)"

#### Details

Product Status	Obsolete
Core Processor	XC800
Core Size	8-Bit
Speed	24MHz
Connectivity	CANbus, SSI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	34
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	1.75K x 8
Voltage - Supply (Vcc/Vdd)	4.5V ~ 5.5V
Data Converters	A/D 8x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	PG-TQFP-48
Purchase URL	<a href="https://www.e-xfl.com/product-detail/infineon-technologies/saf-xc886cm-8ffa-5v-ac">https://www.e-xfl.com/product-detail/infineon-technologies/saf-xc886cm-8ffa-5v-ac</a>

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## Summary of Features

### Features: (continued)

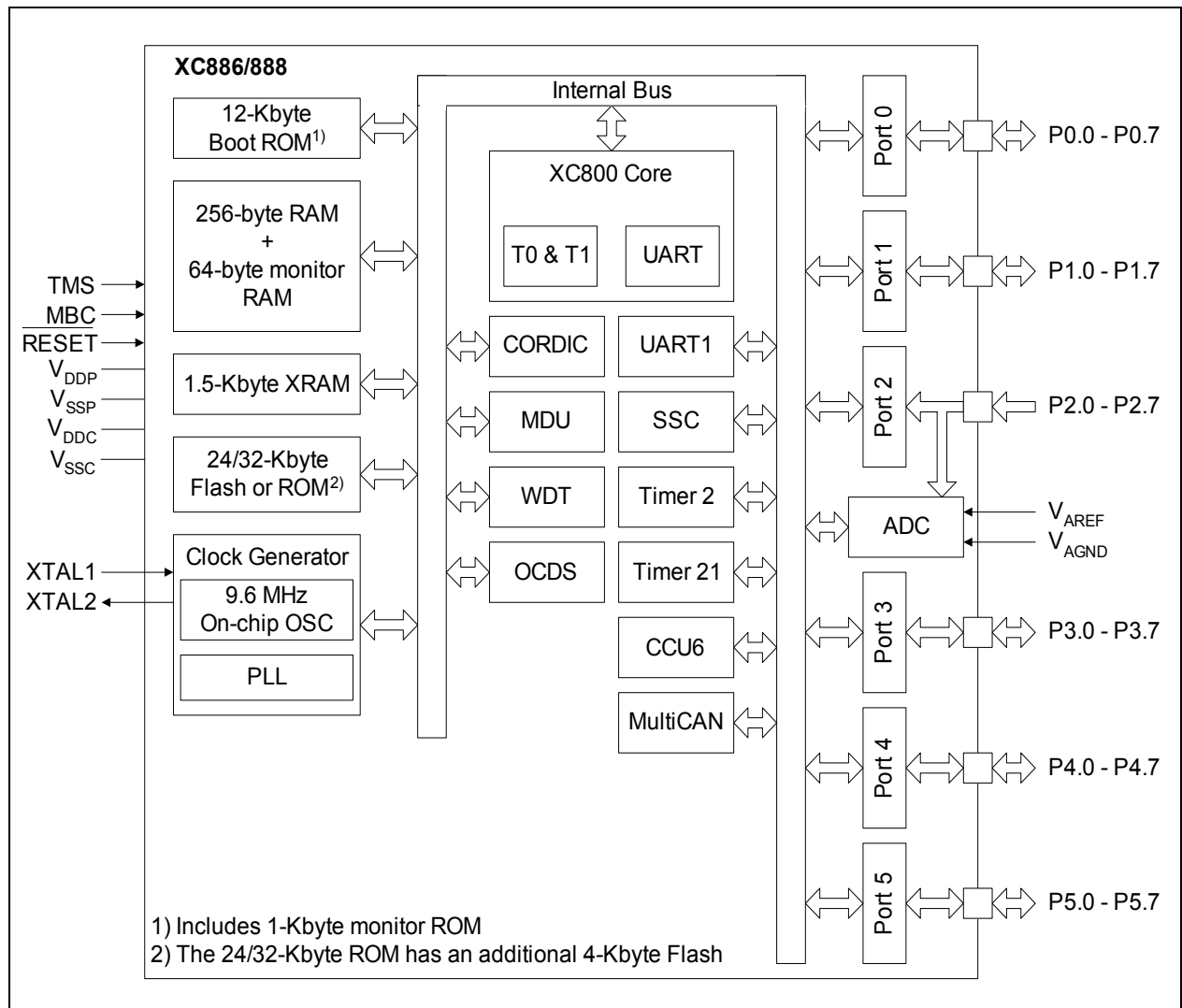
- Power-on reset generation
- Brownout detection for core logic supply
- On-chip OSC and PLL for clock generation
  - PLL loss-of-lock detection
- Power saving modes
  - slow-down mode
  - idle mode
  - power-down mode with wake-up capability via RXD or EXINT0
  - clock gating control to each peripheral
- Programmable 16-bit Watchdog Timer (WDT)
- Six ports
  - Up to 48 pins as digital I/O
  - 8 pins as digital/analog input
- 8-channel, 10-bit ADC
- Four 16-bit timers
  - Timer 0 and Timer 1 (T0 and T1)
  - Timer 2 and Timer 21 (T2 and T21)
- Multiplication/Division Unit for arithmetic operations (MDU)
- Software libraries to support floating point and MDU calculations
- CORDIC Coprocessor for computation of trigonometric, hyperbolic and linear functions
- MultiCAN with 2 nodes, 32 message objects
- Capture/compare unit for PWM signal generation (CCU6)
- Two full-duplex serial interfaces (UART and UART1)
- Synchronous serial channel (SSC)
- On-chip debug support
  - 1 Kbyte of monitor ROM (part of the 12-Kbyte Boot ROM)
  - 64 bytes of monitor RAM
- Packages:
  - PG-TQFP-48
  - PG-TQFP-64
- Temperature range  $T_A$ :
  - SAF (-40 to 85 °C)
  - SAK (-40 to 125 °C)

## 2 General Device Information

**Chapter 2** contains the block diagram, pin configurations, definitions and functions of the XC886/888.

### 2.1 Block Diagram

The block diagram of the XC886/888 is shown in **Figure 2**.



**Figure 2 XC886/888 Block Diagram**



**General Device Information**
**2.4 Pin Definitions and Functions**

The functions and default states of the XC886/888 external pins are provided in [Table 3](#).

**Table 3 Pin Definitions and Functions**

Symbol	Pin Number (TQFP-48/64)	Type	Reset State	Function
<b>P0</b>		I/O		<b>Port 0</b> Port 0 is an 8-bit bidirectional general purpose I/O port. It can be used as alternate functions for the JTAG, CCU6, UART, UART1, Timer 2, Timer 21, MultiCAN and SSC.
P0.0	11/17		Hi-Z	<div>TCK_0 JTAG Clock Input</div> <div>T12HR_1 CCU6 Timer 12 Hardware Run Input</div> <div>CC61_1 Input/Output of Capture/Compare channel 1</div> <div>CLKOUT_0 Clock Output</div> <div>RXDO_1 UART Transmit Data Output</div>
P0.1	13/21		Hi-Z	<div>TDI_0 JTAG Serial Data Input</div> <div>T13HR_1 CCU6 Timer 13 Hardware Run Input</div> <div>RXD_1 UART Receive Data Input</div> <div>RXDC1_0 MultiCAN Node 1 Receiver Input</div> <div>COUT61_1 Output of Capture/Compare channel 1</div> <div>EXF2_1 Timer 2 External Flag Output</div>
P0.2	12/18		PU	<div>CTRAP_2 CCU6 Trap Input</div> <div>TDO_0 JTAG Serial Data Output</div> <div>TXD_1 UART Transmit Data Output/Clock Output</div> <div>TXDC1_0 MultiCAN Node 1 Transmitter Output</div>
P0.3	48/63		Hi-Z	<div>SCK_1 SSC Clock Input/Output</div> <div>COUT63_1 Output of Capture/Compare channel 3</div> <div>RXDO1_0 UART1 Transmit Data Output</div>

## General Device Information

Table 3 Pin Definitions and Functions (cont'd)

Symbol	Pin Number (TQFP-48/64)	Type	Reset State	Function
P2		I		<b>Port 2</b> Port 2 is an 8-bit general purpose input-only port. It can be used as alternate functions for the digital inputs of the JTAG and CCU6. It is also used as the analog inputs for the ADC.
P2.0	14/22		Hi-Z	CCPOS0_0 CCU6 Hall Input 0 EXINT1_0 External Interrupt Input 1 T12HR_2 CCU6 Timer 12 Hardware Run Input TCK_1 JTAG Clock Input CC61_3 Input of Capture/Compare channel 1 AN0 Analog Input 0
P2.1	15/23		Hi-Z	CCPOS1_0 CCU6 Hall Input 1 EXINT2_0 External Interrupt Input 2 T13HR_2 CCU6 Timer 13 Hardware Run Input TDI_1 JTAG Serial Data Input CC62_3 Input of Capture/Compare channel 2 AN1 Analog Input 1
P2.2	16/24		Hi-Z	CCPOS2_0 CCU6 Hall Input 2 CTRAP_1 CCU6 Trap Input CC60_3 Input of Capture/Compare channel 0 AN2 Analog Input 2
P2.3	19/27		Hi-Z	AN3 Analog Input 3
P2.4	20/28		Hi-Z	AN4 Analog Input 4
P2.5	21/29		Hi-Z	AN5 Analog Input 5
P2.6	22/30		Hi-Z	AN6 Analog Input 6
P2.7	25/33		Hi-Z	AN7 Analog Input 7

## Functional Description

code or data. Therefore, even though the ROM device contains either a 24-Kbyte or 32-Kbyte ROM, the maximum size of code that can be placed in the ROM is the given size less four bytes.

### 3.2.1 Memory Protection Strategy

The XC886/888 memory protection strategy includes:

- Read-out protection: The user is able to protect the contents in the Flash (for Flash devices) and ROM (for ROM devices) memory from being read
  - Flash protection is enabled by programming a valid password (8-bit non-zero value) via BSL mode 6.
  - ROM protection is fixed with the ROM mask and is always enabled.
- Flash program and erase protection: This feature is available only for Flash devices.

#### 3.2.1.1 Flash Memory Protection

As long as a valid password is available, all external access to the device, including the Flash, will be blocked.

For additional security, the Flash hardware protection can be enabled to implement a second layer of read-out protection, as well as to enable program and erase protection.

Flash hardware protection is available only for Flash devices and comes in two modes:

- Mode 0: Only the P-Flash is protected; the D-Flash is unprotected
- Mode 1: Both the P-Flash and D-Flash are protected

The selection of each protection mode and the restrictions imposed are summarized in [Table 4](#).

**Table 4 Flash Protection Modes**

Flash Protection	Without hardware protection			With hardware protection	
Hardware Protection Mode	-	0	1		
Activation	Program a valid password via BSL mode 6				
Selection	Bit 4 of password = 0	Bit 4 of password = 1	MSB of password = 0	Bit 4 of password = 1	MSB of password = 1
P-Flash contents can be read by	Read instructions in any program memory	Read instructions in the P-Flash		Read instructions in the P-Flash or D-Flash	
External access to P-Flash	Not possible	Not possible		Not possible	



## Functional Description

**Table 4 Flash Protection Modes (cont'd)**

Flash Protection	Without hardware protection	With hardware protection	
<b>P-Flash program and erase</b>	Possible	Not possible	Not possible
<b>D-Flash contents can be read by</b>	Read instructions in any program memory	Read instructions in any program memory	Read instructions in the P-Flash or D-Flash
<b>External access to D-Flash</b>	Not possible	Not possible	Not possible
<b>D-Flash program</b>	Possible	Possible	Not possible
<b>D-Flash erase</b>	Possible	Possible, on condition that bit DFLASHEN in register MISC_CON is set to 1 prior to each erase operation	Not possible

BSL mode 6, which is used for enabling Flash protection, can also be used for disabling Flash protection. Here, the programmed password must be provided by the user. A password match triggers an automatic erase of the protected P-Flash and D-Flash contents, including the programmed password. The Flash protection is then disabled upon the next reset.

For the ROM device, the ROM is protected at all times and BSL mode 6 is used only to block external access to the device. However, unlike the Flash device, it is not possible to disable the memory protection of the ROM device. Here, entering BSL mode 6 will result in a protection error.

*Note: If ROM read-out protection is enabled, only read instructions in the ROM memory can target the ROM contents.*

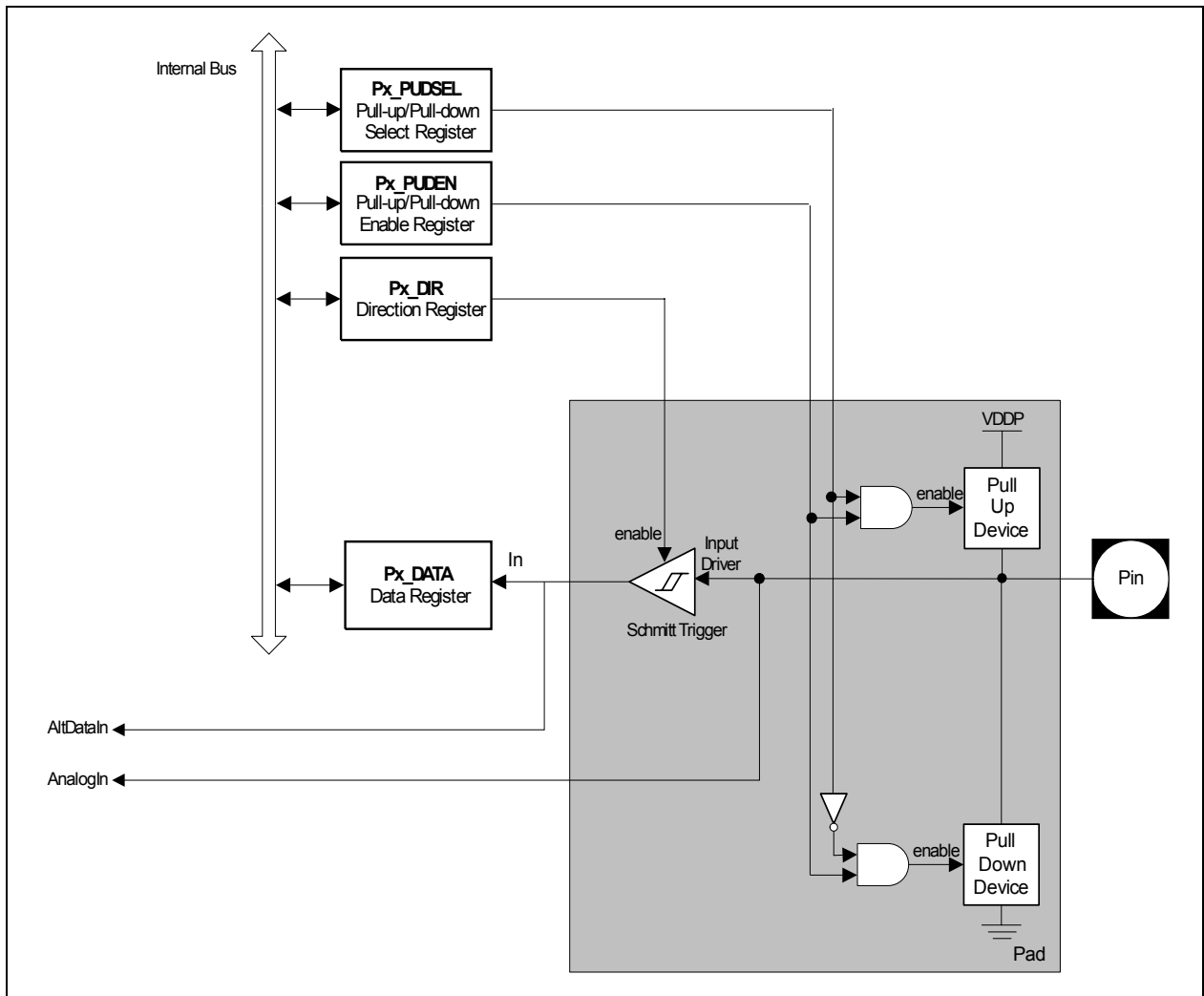
Although no protection scheme can be considered infallible, the XC886/888 memory protection strategy provides a very high level of protection for a general purpose microcontroller.

**Functional Description**
**Table 11 ADC Register Overview (cont'd)**

Addr	Register Name	Bit	7	6	5	4	3	2	1	0
CC <sub>H</sub>	<b>ADC_CHINSR</b> <b>Reset: 00<sub>H</sub></b> Channel Interrupt Set Register	Bit Field	CHINS 7	CHINS 6	CHINS 5	CHINS 4	CHINS 3	CHINS 2	CHINS 1	CHINS 0
		Type	w	w	w	w	w	w	w	w
CD <sub>H</sub>	<b>ADC_CHINPR</b> <b>Reset: 00<sub>H</sub></b> Channel Interrupt Node Pointer Register	Bit Field	CHINP 7	CHINP 6	CHINP 5	CHINP 4	CHINP 3	CHINP 2	CHINP 1	CHINP 0
		Type	rw	rw	rw	rw	rw	rw	rw	rw
CE <sub>H</sub>	<b>ADC_EVINFR</b> <b>Reset: 00<sub>H</sub></b> Event Interrupt Flag Register	Bit Field	EVINF 7	EVINF 6	EVINF 5	EVINF 4	0		EVINF 1	EVINF 0
		Type	rh	rh	rh	rh	r		rh	rh
CF <sub>H</sub>	<b>ADC_EVINCR</b> <b>Reset: 00<sub>H</sub></b> Event Interrupt Clear Flag Register	Bit Field	EVINC 7	EVINC 6	EVINC 5	EVINC 4	0		EVINC 1	EVINC 0
		Type	w	w	w	w	r		w	w
D2 <sub>H</sub>	<b>ADC_EVINSR</b> <b>Reset: 00<sub>H</sub></b> Event Interrupt Set Flag Register	Bit Field	EVINS 7	EVINS 6	EVINS 5	EVINS 4	0		EVINS 1	EVINS 0
		Type	w	w	w	w	r		w	w
D3 <sub>H</sub>	<b>ADC_EVINPR</b> <b>Reset: 00<sub>H</sub></b> Event Interrupt Node Pointer Register	Bit Field	EVINP 7	EVINP 6	EVINP 5	EVINP 4	0		EVINP 1	EVINP 0
		Type	rw	rw	rw	rw	r		rw	rw
RMAP = 0, PAGE 6										
CA <sub>H</sub>	<b>ADC_CRCR1</b> <b>Reset: 00<sub>H</sub></b> Conversion Request Control Register 1	Bit Field	CH7	CH6	CH5	CH4	0			
		Type	rwh	rwh	rwh	rwh	r			
CB <sub>H</sub>	<b>ADC_CRPR1</b> <b>Reset: 00<sub>H</sub></b> Conversion Request Pending Register 1	Bit Field	CHP7	CHP6	CHP5	CHP4	0			
		Type	rwh	rwh	rwh	rwh	r			
CC <sub>H</sub>	<b>ADC_CMR1</b> <b>Reset: 00<sub>H</sub></b> Conversion Request Mode Register 1	Bit Field	Rsv	LDEV	CLRP ND	SCAN	ENSI	ENTR	0	ENGT
		Type	r	w	w	rw	rw	rw	r	rw
CD <sub>H</sub>	<b>ADC_QMR0</b> <b>Reset: 00<sub>H</sub></b> Queue Mode Register 0	Bit Field	CEV	TREV	FLUS H	CLRV	0	ENTR	0	ENGT
		Type	w	w	w	w	r	rw	r	rw
CE <sub>H</sub>	<b>ADC_QSR0</b> <b>Reset: 20<sub>H</sub></b> Queue Status Register 0	Bit Field	Rsv	0	EMPT Y	EV	0		FILL	
		Type	r	r	rh	rh	r		rh	
CF <sub>H</sub>	<b>ADC_Q0R0</b> <b>Reset: 00<sub>H</sub></b> Queue 0 Register 0	Bit Field	EXTR	ENSI	RF	V	0	REQCHNR		
		Type	rh	rh	rh	rh	r	rh		
D2 <sub>H</sub>	<b>ADC_QBUR0</b> <b>Reset: 00<sub>H</sub></b> Queue Backup Register 0	Bit Field	EXTR	ENSI	RF	V	0	REQCHNR		
		Type	rh	rh	rh	rh	r	rh		
D2 <sub>H</sub>	<b>ADC_QINR0</b> <b>Reset: 00<sub>H</sub></b> Queue Input Register 0	Bit Field	EXTR	ENSI	RF	0		REQCHNR		
		Type	w	w	w	r		w		

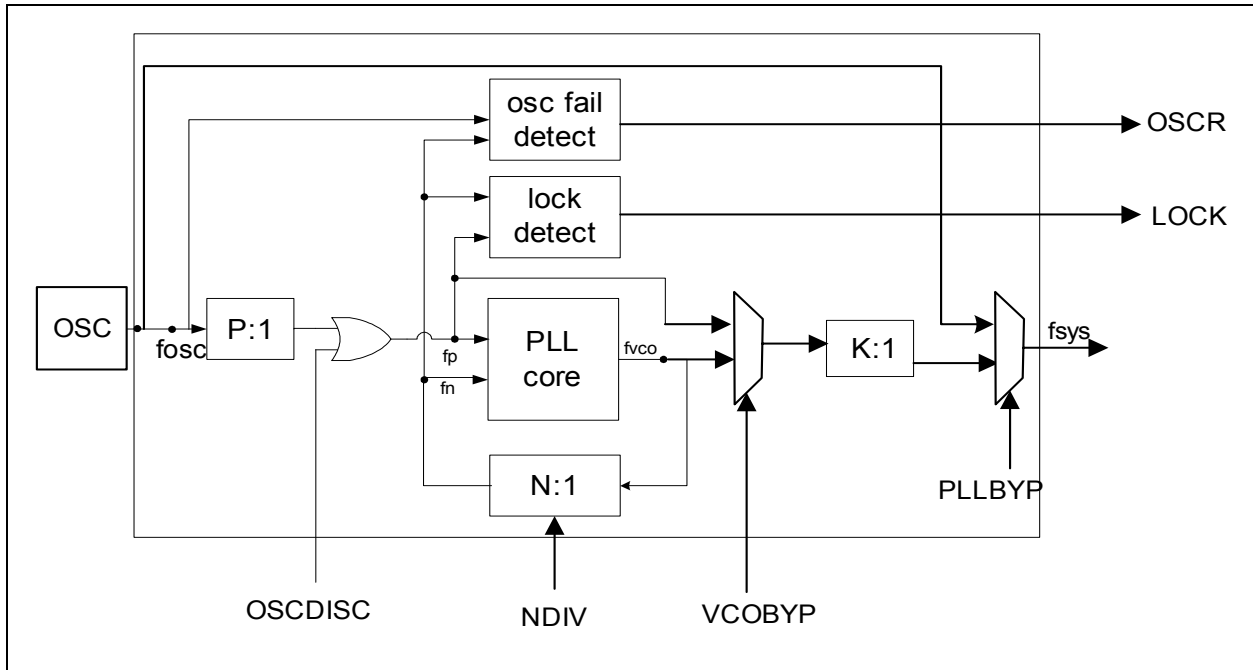
## Functional Description

**Figure 20** shows the structure of an input-only port pin.



**Figure 20** General Structure of Input Port

## Functional Description



**Figure 24 CGU Block Diagram**

### PLL Base Mode

When the oscillator is disconnected from the PLL, the system clock is derived from the VCO base (free running) frequency clock ([Table 25](#)) divided by the K factor.

$$f_{SYS} = f_{VCObase} \times \frac{1}{K}$$

(3.1)

### Prescaler Mode (VCO Bypass Operation)

In VCO bypass operation, the system clock is derived from the oscillator clock, divided by the P and K factors.

$$f_{SYS} = f_{OSC} \times \frac{1}{P \times K}$$

(3.2)

## Functional Description

**Table 25** shows the VCO range for the XC886/888.

**Table 25 VCO Range**

$f_{VCOmin}$	$f_{VCOmax}$	$f_{VCOFREEmin}$	$f_{VCOFREEmax}$	Unit
150	200	20	80	MHz
100	150	10	80	MHz

### 3.8.1 Recommended External Oscillator Circuits

The oscillator circuit, a Pierce oscillator, is designed to work with both, an external crystal oscillator or an external stable clock source. It basically consists of an inverting amplifier and a feedback element with XTAL1 as input, and XTAL2 as output.

When using a crystal, a proper external oscillator circuitry must be connected to both pins, XTAL1 and XTAL2. The crystal frequency can be within the range of 4 MHz to 12 MHz. Additionally, it is necessary to have two load capacitances  $C_{X1}$  and  $C_{X2}$ , and depending on the crystal type, a series resistor  $R_{X2}$ , to limit the current. A test resistor  $R_Q$  may be temporarily inserted to measure the oscillation allowance (negative resistance) of the oscillator circuitry.  $R_Q$  values are typically specified by the crystal vendor. The  $C_{X1}$  and  $C_{X2}$  values shown in **Figure 25** can be used as starting points for the negative resistance evaluation and for non-productive systems. The exact values and related operating range are dependent on the crystal frequency and have to be determined and optimized together with the crystal vendor using the negative resistance method. Oscillation measurement with the final target system is strongly recommended to verify the input amplitude at XTAL1 and to determine the actual oscillation allowance (margin negative resistance) for the oscillator-crystal system.

When using an external clock signal, the signal must be connected to XTAL1. XTAL2 is left open (unconnected).

The oscillator can also be used in combination with a ceramic resonator. The final circuitry must also be verified by the resonator vendor. **Figure 25** shows the recommended external oscillator circuitries for both operating modes, external crystal mode and external input clock mode.

## Functional Description

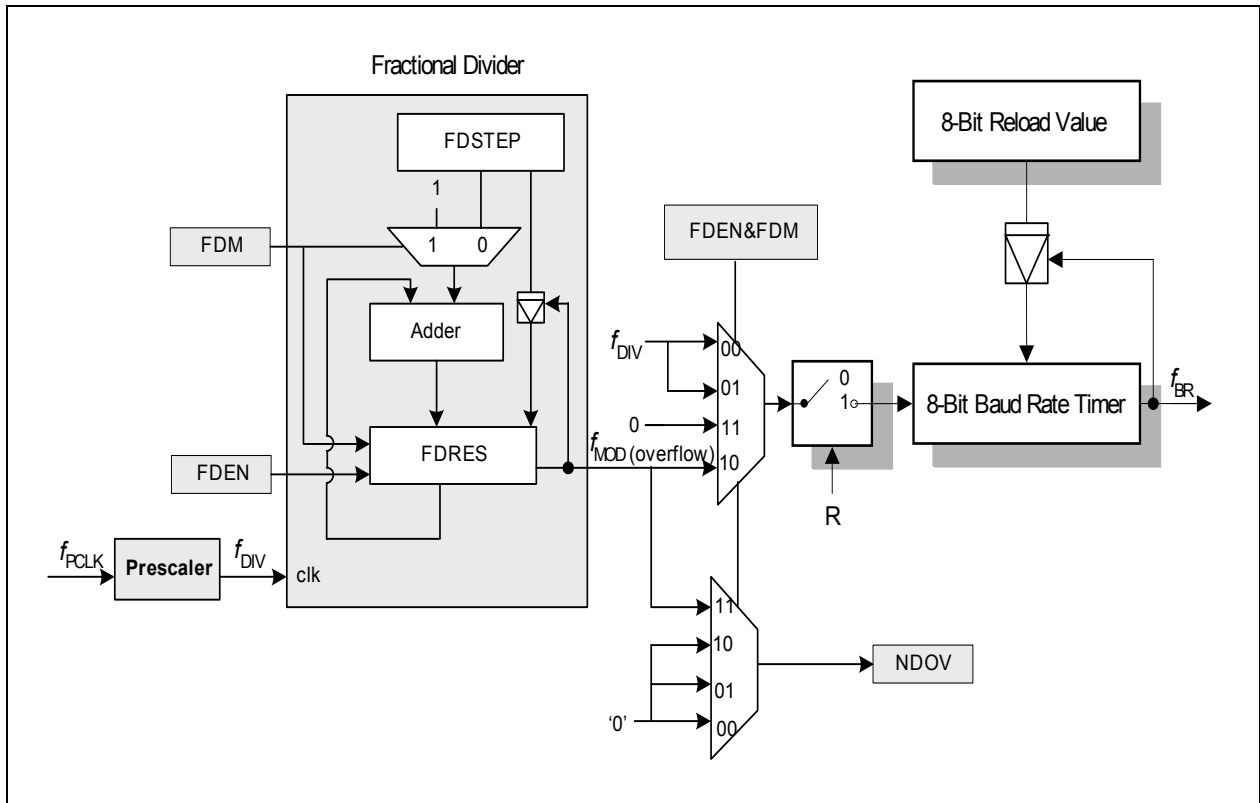
For power saving purposes, the clocks may be disabled or slowed down according to [Table 26](#).

**Table 26**      **System frequency ( $f_{\text{sys}} = 96 \text{ MHz}$ )**

Power Saving Mode	Action
Idle	Clock to the CPU is disabled.
Slow-down	Clocks to the CPU and all the peripherals are divided by a common programmable factor defined by bit field CMCON.CLKREL.
Power-down	Oscillator and PLL are switched off.

## Functional Description

fractional divider) for generating a wide range of baud rates based on its input clock  $f_{PCLK}$ , see [Figure 30](#).



**Figure 30 Baud-rate Generator Circuitry**

The baud rate timer is a count-down timer and is clocked by either the output of the fractional divider ( $f_{MOD}$ ) if the fractional divider is enabled (FDCON.FDEN = 1), or the output of the prescaler ( $f_{DIV}$ ) if the fractional divider is disabled (FDEN = 0). For baud rate generation, the fractional divider must be configured to fractional divider mode (FDCON.FDM = 0). This allows the baud rate control run bit BCON.R to be used to start or stop the baud rate timer. At each timer underflow, the timer is reloaded with the 8-bit reload value in register BG and one clock pulse is generated for the serial channel.

Enabling the fractional divider in normal divider mode (FDEN = 1 and FDM = 1) stops the baud rate timer and nullifies the effect of bit BCON.R. See [Section 3.14](#).

The baud rate ( $f_{BR}$ ) value is dependent on the following parameters:

- Input clock  $f_{PCLK}$
- Prescaling factor ( $2^{BRPRE}$ ) defined by bit field BRPRE in register BCON
- Fractional divider (STEP/256) defined by register FDSTEP  
(to be considered only if fractional divider is enabled and operating in fractional divider mode)
- 8-bit reload value (BR\_VALUE) for the baud rate timer defined by register BG

## Functional Description

### 3.18 Timer 2 and Timer 21

Timer 2 and Timer 21 are 16-bit general purpose timers (THL2) that are fully compatible and have two modes of operation, a 16-bit auto-reload mode and a 16-bit one channel capture mode, see [Table 33](#). As a timer, the timers count with an input clock of PCLK/12 (if prescaler is disabled). As a counter, they count 1-to-0 transitions on pin T2. In the counter mode, the maximum resolution for the count is PCLK/24 (if prescaler is disabled).

**Table 33 Timer 2 Modes**

Mode	Description
Auto-reload	<b>Up/Down Count Disabled</b> <ul style="list-style-type: none"> <li>Count up only</li> <li>Start counting from 16-bit reload value, overflow at FFFF<sub>H</sub></li> <li>Reload event configurable for trigger by overflow condition only, or by negative/positive edge at input pin T2EX as well</li> <li>Programmable reload value in register RC2</li> <li>Interrupt is generated with reload event</li> </ul>
	<b>Up/Down Count Enabled</b> <ul style="list-style-type: none"> <li>Count up or down, direction determined by level at input pin T2EX</li> <li>No interrupt is generated</li> <li>Count up <ul style="list-style-type: none"> <li>Start counting from 16-bit reload value, overflow at FFFF<sub>H</sub></li> <li>Reload event triggered by overflow condition</li> <li>Programmable reload value in register RC2</li> </ul> </li> <li>Count down <ul style="list-style-type: none"> <li>Start counting from FFFF<sub>H</sub>, underflow at value defined in register RC2</li> <li>Reload event triggered by underflow condition</li> <li>Reload value fixed at FFFF<sub>H</sub></li> </ul> </li> </ul>
Channel capture	<ul style="list-style-type: none"> <li>Count up only</li> <li>Start counting from 0000<sub>H</sub>, overflow at FFFF<sub>H</sub></li> <li>Reload event triggered by overflow condition</li> <li>Reload value fixed at 0000<sub>H</sub></li> <li>Capture event triggered by falling/rising edge at pin T2EX</li> <li>Captured timer value stored in register RC2</li> <li>Interrupt is generated with reload or capture event</li> </ul>



**Electrical Parameters**
**Table 38 Input/Output Characteristics (Operating Conditions apply) (cont'd)**

Parameter	Symbol		Limit Values		Unit	Test Conditions
			min.	max.		
Maximum current out of $V_{SS}$	$I_{MVSS}$	SR	–	120	mA	<sup>3)</sup>
<b><math>V_{DDP} = 3.3 \text{ V Range}</math></b>						
Output low voltage	$V_{OL}$	CC	–	1.0	V	$I_{OL} = 8 \text{ mA}$
			–	0.4	V	$I_{OL} = 2.5 \text{ mA}$
Output high voltage	$V_{OH}$	CC	$V_{DDP} - 1.0$	–	V	$I_{OH} = -8 \text{ mA}$
			$V_{DDP} - 0.4$	–	V	$I_{OH} = -2.5 \text{ mA}$
Input low voltage on port pins (all except P0.0 & P0.1)	$V_{ILP}$	SR	–	$0.3 \times V_{DDP}$	V	CMOS Mode
Input low voltage on P0.0 & P0.1	$V_{ILP0}$	SR	-0.2	$0.3 \times V_{DDP}$	V	CMOS Mode
Input low voltage on RESET pin	$V_{ILR}$	SR	–	$0.3 \times V_{DDP}$	V	CMOS Mode
Input low voltage on TMS pin	$V_{ILT}$	SR	–	$0.3 \times V_{DDP}$	V	CMOS Mode
Input high voltage on port pins (all except P0.0 & P0.1)	$V_{IHP}$	SR	$0.7 \times V_{DDP}$	–	V	CMOS Mode
Input high voltage on P0.0 & P0.1	$V_{IHP0}$	SR	$0.7 \times V_{DDP}$	$V_{DDP}$	V	CMOS Mode
Input high voltage on RESET pin	$V_{IHR}$	SR	$0.7 \times V_{DDP}$	–	V	CMOS Mode
Input high voltage on TMS pin	$V_{IHT}$	SR	$0.75 \times V_{DDP}$	–	V	CMOS Mode
Input Hysteresis	$HYS$	CC	$0.03 \times V_{DDP}$	–	V	CMOS Mode <sup>1)</sup>
Input Hysteresis on XTAL1	$HYSX$	CC	$0.07 \times V_{DDC}$	–	V	<sup>1)</sup>
Input low voltage at XTAL1	$V_{ILX}$	SR	$V_{SS} - 0.5$	$0.3 \times V_{DDC}$	V	

**Electrical Parameters**
**Table 40 ADC Characteristics (Operating Conditions apply;  $V_{DDP} = 5V$  Range)**

Parameter	Symbol		Limit Values			Unit	Test Conditions/ Remarks
			min.	typ .	max.		
Overload current coupling factor for digital I/O pins	$K_{OVD}$	CC	–	–	$5.0 \times 10^{-3}$	–	$I_{OV} > 0^{1)3)}$
			–	–	$1.0 \times 10^{-2}$	–	$I_{OV} < 0^{1)3)}$
Switched capacitance at the reference voltage input	$C_{AREFSW}$	CC	–	10	20	pF	1)4)
Switched capacitance at the analog voltage inputs	$C_{AINSW}$	CC	–	5	7	pF	1)5)
Input resistance of the reference input	$R_{AREF}$	CC	–	1	2	k $\Omega$	1)
Input resistance of the selected analog channel	$R_{AIN}$	CC	–	1	1.5	k $\Omega$	1)

1) Not subjected to production test, verified by design/characterization

2) TUE is tested at  $V_{AREF} = 5.0 V$ ,  $V_{AGND} = 0 V$ ,  $V_{DDP} = 5.0 V$ .

3) An overload current ( $I_{OV}$ ) through a pin injects a certain error current ( $I_{INJ}$ ) into the adjacent pins. This error current adds to the respective pin's leakage current ( $I_{OZ}$ ). The amount of error current depends on the overload current and is defined by the overload coupling factor  $K_{OV}$ . The polarity of the injected error current is inverse compared to the polarity of the overload current that produces it. The total current through a pin is  $|I_{TOT}| = |I_{OZ1}| + (|I_{OV}| \times K_{OV})$ . The additional error current may distort the input voltage on analog inputs.

4) This represents an equivalent switched capacitance. This capacitance is not switched to the reference voltage at once. Instead of this, smaller capacitances are successively switched to the reference voltage.

5) The sampling capacity of the conversion C-Network is pre-charged to  $V_{AREF}/2$  before connecting the input to the C-Network. Because of the parasitic elements, the voltage measured at ANx is lower than  $V_{AREF}/2$ .

#### 4.2.3.1 ADC Conversion Timing

Conversion time,  $t_C = t_{ADC} \times (1 + r \times (3 + n + \text{STC}))$ , where

$r = \text{CTC} + 2$  for  $\text{CTC} = 00_B, 01_B$  or  $10_B$ ,

$r = 32$  for  $\text{CTC} = 11_B$ ,

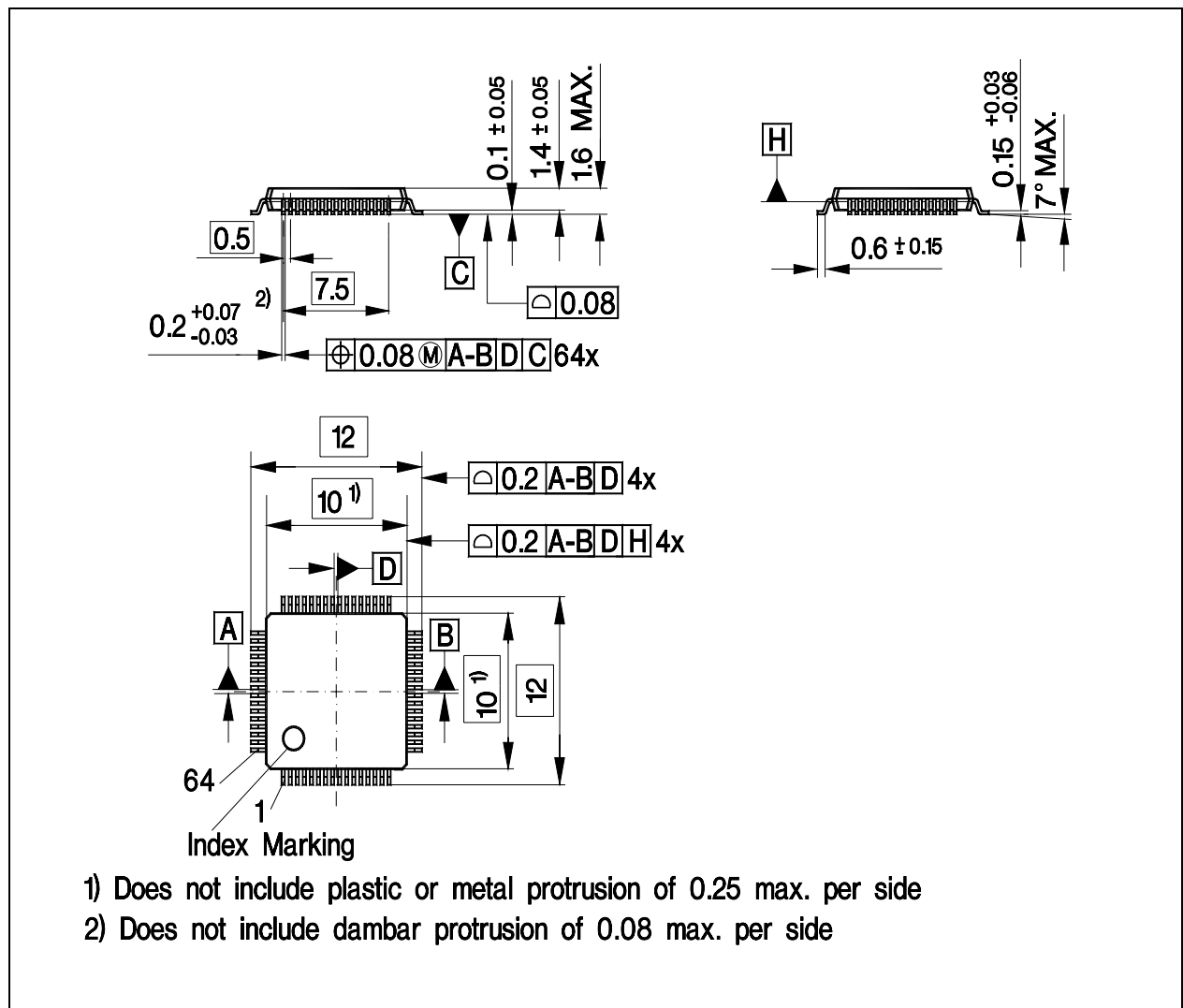
$\text{CTC}$  = Conversion Time Control (GLOBCTR.CTC),

$\text{STC}$  = Sample Time Control (INPCR0.STC),

$n = 8$  or  $10$  (for 8-bit and 10-bit conversion respectively),

$t_{ADC} = 1 / f_{ADC}$

**Figure 49** shows the package outlines of the XC888.



**Figure 49 PG-TQFP-64 Package Outline**

**Package and Quality Declaration**
**5.3 Quality Declaration**

**Table 2** shows the characteristics of the quality parameters in the XC886/888.

**Table 2 Quality Parameters**

Parameter	Symbol	Limit Values		Unit	Notes
		Min.	Max.		
ESD susceptibility according to Human Body Model (HBM)	$V_{\text{HBM}}$	-	2000	V	Conforming to EIA/JESD22-A114-B <sup>1)</sup>
ESD susceptibility according to Charged Device Model (CDM) pins	$V_{\text{CDM}}$	-	500	V	Conforming to JESD22-C101-C <sup>1)</sup>

1) Not all parameters are 100% tested, but are verified by design/characterization and test correlation.